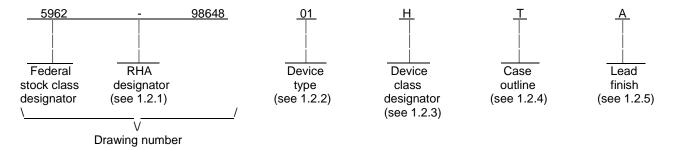
	REVISIONS		
LTR	DESCRIPTION	DATE (YR-MO-DA)	APPROVED
Α	Update drawing to reflect current requirements.	05-01-25	Raymond Monnin
В	Updated drawing paragraphssld	11-03-07	Charles F. Saffle
С	Add case outline Y. Table I; correct max limit for "Thermal regulation" test from "0.15" to "0.015"gc	14-03-13	Charles F. Saffle
D	Add case outline Mgc	14-09-03	Charles F. Saffle
E	Add case outline 4. Paragraph 1.3, "Thermal resistance, junction-to-case $(\theta_{JC})$ " add case outline M reference for 3.0°C/W. Figure 2 terminal corrections remove reference to case outline X. $-gc$	15-01-05	Charles F. Saffle



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## 1. SCOPE

- 1.1 <u>Scope</u>. This drawing documents five product assurance classes as defined in paragraph 1.2.3 and MIL-PRF-38534. A choice of case outlines and lead finishes which are available and are reflected in the Part or Identifying Number (PIN). When available, a choice of radiation hardness assurance levels are reflected in the PIN.
  - 1.2 PIN. The PIN shall be as shown in the following example:



- 1.2.1 <u>Radiation hardness assurance (RHA) designator</u>. RHA marked devices shall meet the MIL-PRF-38534 specified RHA levels and shall be marked with the appropriate RHA designator. A dash (-) indicates a non-RHA device.
  - 1.2.2 <u>Device type(s)</u>. The device type(s) identify the circuit function as follows:

Device type	Generic number 1/	Circuit function
01	SDP1084	5.0 A, positive voltage regulator, adjustable, low dropout

1.2.3 <u>Device class designator</u>. This device class designator shall be a single letter identifying the product assurance level. All levels are defined by the requirements of MIL-PRF-38534 and require QML Certification as well as qualification (Class H, K, and E) or QML Listing (Class G and D). The product assurance levels are as follows:

<u>Device class</u>	Device performance documentation
К	Highest reliability class available. This level is intended for use in space applications.
Н	Standard military quality class level. This level is intended for use in applications where non-space high reliability devices are required.
G	Reduced testing version of the standard military quality class. This level uses the Class H screening and In-Process Inspections with a possible limited temperature range, manufacturer specified incoming flow, and the manufacturer guarantees (but may not test) periodic and conformance inspections (Group A, B, C and D).
E	Designates devices which are based upon one of the other classes (K, H, or G) with exception(s) taken to the requirements of that class. These exception(s) must be specified in the device acquisition document; therefore the acquisition document should be reviewed to ensure that the exception(s) taken will not adversely affect system performance.
D	Manufacturer specified quality class. Quality level is defined by the manufacturers internal, QML certified flow. This product may have a limited temperature range.

1/ The SDP1084 is similar to the AS1084 or LT1084 or OM184 or OM1840 listed on Standard Microcircuit Drawing 5962-89521.

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1.2.4 <u>Case outline(s)</u>. The case outline(s) are as designated in MIL-STD-1835 and as follows:

Outline letter	Descriptive designator	<u>Terminals</u>	Package style
4	See figure 1	3	Flange mount with nonisolated tab, (TO-258), with ceramic seal
M	See figure 1	3	Flange mount with isolated tab, (TO-258), with ceramic seal
N	See figure 1	3	Z-tab with nonisolated tab, (TO-259), with glass seal
Т	See figure 1	3	Flange mount with nonisolated tab, (TO-258), with glass seal
U	See figure 1	3	Flange mount with isolated tab, (TO-258), with glass seal
Υ	See figure 1	3	Flange mount with isolated tab, (TO-258), with ceramic seal
Z	See figure 1	3	Z-tab with isolated tab, (TO-259), with glass seal

- 1.2.5 Lead finish. The lead finish shall be as specified in MIL-PRF-38534.
- 1.3 Absolute maximum ratings. 1/

Input to output voltage differential  Output current (I <sub>OUT</sub> )  Storage temperature range  Lead temperature (soldering, 10 seconds)  Junction temperature (T <sub>J</sub> )	35 V dc 5.0 A -65°C to +150°C +300°C +150°C
Power dissipation (P <sub>D</sub> )	Internally limited
Thermal resistance junction-to-case (θ <sub>JC</sub> ):	ou
Case N, T and 4	2.3°C/W
Case U, Y, Z, and M	3.0°C/W
Thermal resistance junction-to-ambient ( $\theta_{JA}$ )	30°C/W

1.4 Recommended operating conditions.

Input to output voltage differential	25 V dc
Output current (I <sub>OUT</sub> )	10 mA minimum
Full load current (I <sub>FL</sub> )	3.0 A
Ambient operating temperature range(T <sub>A</sub> )	-55°C to +125°C

## 2. APPLICABLE DOCUMENTS

2.1 <u>Government specification, standards, and handbooks</u>. The following specification, standards, and handbooks form a part of this drawing to the extent specified herein. Unless otherwise specified, the issues of these documents are those cited in the solicitation or contract.

## DEPARTMENT OF DEFENSE SPECIFICATION

MIL-PRF-38534 - Hybrid Microcircuits, General Specification for.

# DEPARTMENT OF DEFENSE STANDARDS

MIL-STD-883 - Test Method Standard Microcircuits.

MIL-STD-1835 - Interface Standard for Electronic Component Case Outlines.

1/ Stresses above the absolute maximum ratings may cause permanent damage to the device. Extended operation at the maximum levels may degrade performance and affect reliability.

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#### DEPARTMENT OF DEFENSE HANDBOOKS

MIL-HDBK-103 - List of Standard Microcircuit Drawings.
MIL-HDBK-780 - Standard Microcircuit Drawings.

(Copies of these documents are available online at <a href="http://quicksearch.dla.mil">http://quicksearch.dla.mil</a> or from the Standardization Document Order Desk, 700 Robbins Avenue, Building 4D, Philadelphia, PA 19111-5094.)

2.2 <u>Order of precedence</u>. In the event of a conflict between the text of this drawing and the references cited herein, the text of this drawing takes precedence. Nothing in this document, however, supersedes applicable laws and regulations unless a specific exemption has been obtained.

#### 3. REQUIREMENTS

- 3.1 <u>Item requirements</u>. The individual item performance requirements for device classes D, E, G, H, and K shall be in accordance with MIL-PRF-38534. Compliance with MIL-PRF-38534 may include the performance of all tests herein or as designated in the device manufacturer's Quality Management (QM) plan or as designated for the applicable device class. The manufacturer may eliminate, modify or optimize the tests and inspections herein, however the performance requirements as defined in MIL-PRF-38534 shall be met for the applicable device class. In addition, the modification in the QM plan shall not affect the form, fit, or function of the device for the applicable device class.
- 3.2 <u>Design, construction, and physical dimensions</u>. The design, construction, and physical dimensions shall be as specified in MIL-PRF-38534 and herein.
  - 3.2.1 Case outline(s). The case outline(s) shall be in accordance with 1.2.4 herein and figure 1.
  - 3.2.2 Terminal connections. The terminal connections shall be as specified on figure 2.
- 3.3 <u>Electrical performance characteristics</u>. Unless otherwise specified herein, the electrical performance characteristics are as specified in table I and shall apply over the full specified operating temperature range.
- 3.4 <u>Electrical test requirements</u>. The electrical test requirements shall be the subgroups specified in table II. The electrical tests for each subgroup are defined in table I.
- 3.5 <u>Marking of device(s)</u>. Marking of device(s) shall be in accordance with MIL-PRF-38534. The device shall be marked with the PIN listed in 1.2 herein. In addition, the manufacturer's vendor similar PIN may also be marked.
- 3.6 <u>Data</u>. In addition to the general performance requirements of MIL-PRF-38534, the manufacturer of the device described herein shall maintain the electrical test data (variables format) from the initial quality conformance inspection group A lot sample, for each device type listed herein. Also, the data should include a summary of all parameters manually tested, and for those which, if any, are guaranteed. This data shall be maintained under document revision level control by the manufacturer and be made available to the preparing activity (DLA Land and Maritime- VA) upon request.
- 3.7 <u>Certificate of compliance</u>. A certificate of compliance shall be required from a manufacturer in order to supply to this drawing. The certificate of compliance (original copy) submitted to DLA Land and Maritime- VA shall affirm that the manufacturer's product meets the performance requirements of MIL-PRF-38534 and herein.
- 3.8 <u>Certificate of conformance</u>. A certificate of conformance as required in MIL-PRF-38534 shall be provided with each lot of microcircuits delivered to this drawing.

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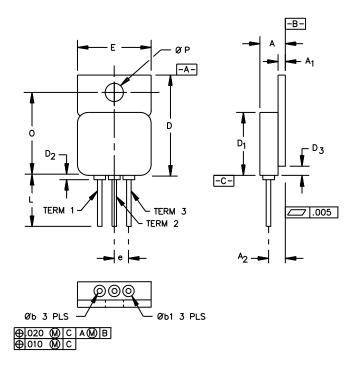
TABLE I. Electrical performance characteristics.							
Test	Symbol	Conditions	Group A	Device	Lin	Unit	
		-55°C ≤ T <sub>A</sub> ≤+125°C unless otherwise specified	subgroups	type	Min	Max	
Reference voltage	$V_{REF}$	$(V_{IN} - V_{OUT}) = 3.0 \text{ V},$ $I_{OUT} = 10 \text{ mA}$	1	01	1.238	1.262	V
		$1.5~V \leq (V_{IN} - V_{OUT}) \leq 25~V,$ $10~mA \leq I_{OUT} \leq 3.0~A$	1,2,3		1.220	1.270	
Line regulation 1/	$\frac{\Delta V_{\text{OUT}}}{\Delta V_{\text{IN}}}$	$1.5~V \leq (V_{IN} - V_{OUT}) \leq 15~V,$ $I_{OUT} = 10~mA$	1	01		0.2	%
	ΔVIN	$1.5~V \leq \left(V_{\text{IN}} - V_{\text{OUT}}\right) \leq 35~V,$ $I_{\text{OUT}} = 10~\text{mA}$	2,3			0.5	
Load regulation 1/	ΔVоυт	$(V_{IN} - V_{OUT}) = 3.0 \text{ V},$ 10 mA \le I <sub>OUT</sub> \le 3.0 A	1	01		0.3	%
	$\Delta l$ оит	10 IIIA 2 1001 2 3.0 A	2,3			0.4	
Dropout voltage	V <sub>DO</sub>	I <sub>OUT</sub> = 3.0 A, ΔV <sub>REF</sub> = 1.0%	1,2,3	01		1.5	V
Thermal regulation		30 ms pulse, T <sub>A</sub> = +25°C	1	01		0.015	%/W
Ripple rejection	$\frac{\Delta V_{\text{IN}}}{\Delta V_{\text{OUT}}}$	$\begin{array}{l} f = 120 \; \text{Hz}, \; C_{\text{ADJ}} = 25 \; \mu\text{F}, \\ C_{\text{OUT}} = 25 \; \mu\text{F} \; (\text{tantalum}), \\ I_{\text{OUT}} = 3.0 \; \text{A}, \\ (V_{\text{IN}} - V_{\text{OUT}}) = 3.0 \; \text{V} \end{array}$	4,5,6	01	60		dB
Adjust pin current	I <sub>ADJ</sub>	$\begin{array}{l} 1.5~V \leq \left(V_{\text{IN}} - V_{\text{OUT}}\right) \leq 25~V, \\ 10~\text{mA} \leq I_{\text{OUT}} \leq 3.0~\text{A} \end{array}$	1,2,3	01		120	μА
Adjust pin current change	$\Delta I_{ADJ}$	$\begin{array}{l} 1.5~V \leq \left(V_{\text{IN}} - V_{\text{OUT}}\right) \leq 25~V, \\ 10~\text{mA} \leq I_{\text{OUT}} \leq 3.0~\text{A} \end{array}$	1,2,3	01		5.0	μА
Minimum load current	I <sub>MIN</sub>	(V <sub>IN</sub> - V <sub>OUT</sub> ) = 25 V	1,2,3	01		10	mA
Current limit	I <sub>LIM</sub>	$(V_{IN} - V_{OUT}) = 5.0 \text{ V}$	1,2,3	01	5.5		Α
		(V <sub>IN</sub> - V <sub>OUT</sub> ) = 25 V			0.3		
Temperature stability 2/	$\Delta V_{OUT}$	-55°C ≤ T <sub>J</sub> ≤ +125°C	1,2,3	01		1.5	%
Long term stability 2/	$\Delta V_OUT$	t =1000 hrs, T <sub>A</sub> = +125°C	2	01		1.0	%

Line and load regulation are measured at a constant junction temperature using a low duty cycle pulse technique. Although power dissipation is internally limited, regulation is guaranteed up to the maximum power dissipation of 45 W. Power dissipation is determined by the input/output differential voltage and the output current. Guaranteed maximum power dissipation will not be available over the full input/output voltage range.

2/ If not tested, shall be guaranteed to the limits specified in table I.

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## Case outline M and 4.



Symbol	Millim	Millimeters Ir		hes
	Min	Max	Min	Max
Α	6.10	6.86	.240	.270
A1	0.89	1.14	.035	.045
A2	3.56	BSC	.140	BSC
øb	1.40	1.65	.055	.065
Øb1	3.91	4.22	.154	.166
D	20.70	21.21	.815	.835
D1	13.46	13.97	.530	.550
D2	1.27	1.78	.050	.070
D3	0.00	2.34	.000	.092
е	5.08	BSC	.200 BSC	
Е	17.40	17.65	.685	.695
L	12.70	19.05	.500	.750
0	17.70	17.96	.697	.707
øΡ	3.94	4.19	.155	.165

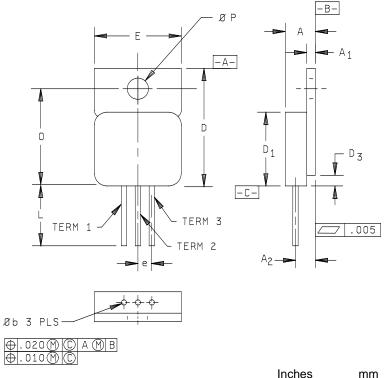
## NOTE:

The U.S. government preferred system of measurement is the metric SI system. However, this item was originally designed using inch-pound units of measurement. In the event of conflict between the metric and inch-pound units, the inch-pound units shall take precedence.

# FIGURE 1. Case outlines.

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# Case outlines T, U, and Y.



<u>Inches</u>	mm
.005	0.13
.010	0.25
.020	0.51

Symbol	Millimeters		Inches	
	Min	Max	Min	Max
Α	6.10	6.86	.240	.270
A1	0.89	1.14	.035	.045
A2	3.56	BSC	.140	BSC
øb	1.40	1.65	.055	.065
D	20.70	21.21	.815	.835
D1	13.46	13.97	.530	.550
D3	0.00	2.34	.000	.092
е	5.08 BSC		.200 BSC	
Е	17.40	17.65	.685	.695
L	12.70	19.05	.500	.750
0	17.70	17.96	.697	.707
øΡ	3.94	4.19	.155	.165

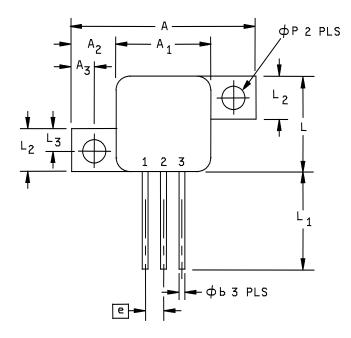
## NOTE:

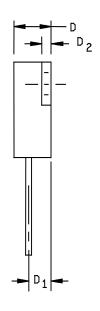
The U.S. government preferred system of measurement is the metric SI system. However, this item was originally designed using inch-pound units of measurement. In the event of conflict between the metric and inch-pound units, the inch-pound units shall take precedence.

FIGURE 1. Case outline(s).

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# Case outlines N and Z.





Symbol	Millim	neters	Inc	hes
	Min	Max	Min	Max
А	30.10	30.35	1.185	1.195
A1	17.40	17.65	.685	.695
A2	6.22	6.48	.245	.255
A3/L3	3.18	BSC	.125 BSC	
øb	1.40	1.65	.055	.065
D	6.10	6.86	.240	.270
D1	3.56 BSC		.140 BSC	
D2	0.89	1.14	.035	.045
е	5.08 BSC		.200 BSC	
L	13.46	13.97	.530	.550
L1	12.70	19.05	.500	.750
L2	6.22	6.48	.245	.255
øΡ	3.05	3.30	.120	.130

## NOTE:

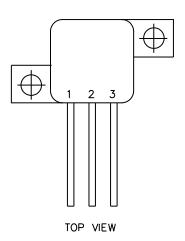
The U.S. government preferred system of measurement is the metric SI system. However, this item was originally designed using inch-pound units of measurement. In the event of conflict between the metric and inch-pound units, the inch-pound units shall take precedence.

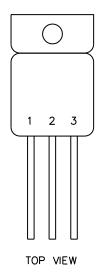
FIGURE 1. Case outline(s) - Continued.

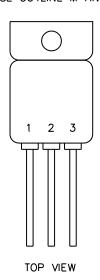
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CASE OUTLINES N AND Z







Device type	01		
Case outlines	N, T, and 4 (nonisolated tab)	M, U, Y, and Z (isolated tab)	
Terminal number	Terminal symbol	Terminal symbol	
1 2 3 Tab	Adjust No connection Input Output	Adjust Output Input No connection	

FIGURE 2. <u>Terminal connections</u>.

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TABLE II. Electrical test requirements.

MIL-PRF-38534 test requirements	Subgroups (in accordance with MIL-PRF-38534, group A test table)
Interim electrical parameters	1
Final electrical parameters	1*, 2, 3, 4, 5, 6
Group A test requirements	1, 2, 3, 4, 5, 6
Group C end-point electrical parameters	1, 2, 3
End-point electrical parameters for Radiation Hardness Assurance (RHA) devices	Not applicable

<sup>\*</sup> PDA applies to subgroup 1.

### 4. VERIFICATION

- 4.1 <u>Sampling and inspection</u>. Sampling and inspection procedures shall be in accordance with MIL-PRF-38534 or as modified in the device manufacturer's Quality Management (QM) plan. The modification in the QM plan shall not affect the form, fit, or function as described herein.
  - 4.2 Screening. Screening shall be in accordance with MIL-PRF-38534. The following additional criteria shall apply:
    - a. Burn-in test, method 1015 of MIL-STD-883.
      - (1) Test condition A, B, C, or D. The test circuit shall be maintained by the manufacturer under document revision level control and shall be made available to either DLA Land and Maritime- VA or the acquiring activity upon request. Also, the test circuit shall specify the inputs, outputs, biases, and power dissipation, as applicable, in accordance with the intent specified in method 1015 of MIL-STD-883.
      - (2) T<sub>A</sub> as specified in accordance with table I of method 1015 of MIL-STD-883.
    - b. Interim and final electrical test parameters shall be as specified in table II herein, except interim electrical parameter tests prior to burn-in are optional at the discretion of the manufacturer.
- 4.3 <u>Conformance and periodic inspections</u>. Conformance inspection (CI) and periodic inspection (PI) shall be in accordance with MIL-PRF-38534 and as specified herein.
  - 4.3.1 Group A inspection (CI). Group A inspection shall be in accordance with MIL-PRF-38534 and as follows:
    - a. Tests shall be as specified in table II herein.
    - b. Subgroups 7, 8, 9, 10, and 11 shall be omitted.
  - 4.3.2 Group B inspection (PI). Group B inspection shall be in accordance with MIL-PRF-38534.

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- 4.3.3 Group C inspection (PI). Group C inspection shall be in accordance with MIL-PRF-38534 and as follows:
  - a. End-point electrical parameters shall be as specified in table II herein.
  - b. Steady-state life test, method 1005 of MIL-STD-883.
    - (1) Test condition A, B, C, or D. The test circuit shall be maintained by the manufacturer under document revision level control and shall be made available to either DLA Land and Maritime- VA or the acquiring activity upon request. Also, the test circuit shall specify the inputs, outputs, biases, and power dissipation, as applicable, in accordance with the intent specified in method 1005 of MIL-STD-883.
    - (2) T<sub>A</sub> as specified in accordance with table I of method 1005 of MIL-STD-883.
    - (3) Test duration: 1,000 hours, except as permitted by method 1005 of MIL-STD-883.
- 4.3.4 Group D inspection (PI). Group D inspection shall be in accordance with MIL-PRF-38534.
- 4.3.5 Radiation Hardness Assurance (RHA) inspection. RHA inspection is not currently applicable to this drawing.
- 5. PACKAGING
- 5.1 Packaging requirements. The requirements for packaging shall be in accordance with MIL-PRF-38534.
- 6. NOTES
- 6.1 <u>Intended use</u>. Microcircuits conforming to this drawing are intended for use for Government microcircuit applications (original equipment), design applications, and logistics purposes.
- 6.2 <u>Replaceability</u>. Microcircuits covered by this drawing will replace the same generic device covered by a contractor-prepared specification or drawing.
- 6.3 <u>Configuration control of SMD's</u>. All proposed changes to existing SMD's will be coordinated as specified in MIL-PRF-38534.
- 6.4 <u>Record of users</u>. Military and industrial users shall inform DLA Land and Maritime- VA when a system application requires configuration control and the applicable SMD. DLA Land and Maritime will maintain a record of users and this list will be used for coordination and distribution of changes to the drawings. Users of drawings covering microelectronic devices (FSC 5962) should contact DLA Land and Maritime- VA, telephone (614) 692-8108.
- 6.5 <u>Comments</u>. Comments on this drawing should be directed to DLA Land and Maritime- VA, Columbus, Ohio 43218-3990, or telephone (614) 692-1081.
- 6.6 <u>Sources of supply</u>. Sources of supply are listed in MIL-HDBK-103 and QML-38534. The vendors listed in MIL-HDBK-103 and QML-38534 have submitted a certificate of compliance (see 3.7 herein) to DLA Land and Maritime- VA and have agreed to this drawing.

STANDARD
MICROCIRCUIT DRAWING
DLA LAND AND MARITIME

COLUMBUS, OHIO 43218-3990

SIZE <b>A</b>		5962-98648
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#### STANDARD MICROCIRCUIT DRAWING BULLETIN

DATE: 15-01-05

Approved sources of supply for SMD 5962-98648 are listed below for immediate acquisition information only and shall be added to MIL-HDBK-103 and QML-38534 during the next revisions. MIL-HDBK-103 and QML-38534 will be revised to include the addition or deletion of sources. The vendors listed below have agreed to this drawing and a certificate of compliance has been submitted to and accepted by DLA Land and Maritime- VA. This information bulletin is superseded by the next dated revisions of MIL-HDBK-103 and QML-38534. DLA Land and Maritime maintains an online database of all current sources of supply at <a href="http://www.landandmaritime.dla.mil/Programs/Smcr/">http://www.landandmaritime.dla.mil/Programs/Smcr/</a>.

Standard	Vendor	Vendor
microcircuit drawing	CAGE	similar
PIN <u>1</u> / <u>2</u> /	number	PIN <u>3</u> /
5962-9864801H4A	21845	SDP10844HD
5962-9864801H4C	21845	SDP10844HG
5962-9864801HMA	21845	SDP1084MHD
5962-9864801HMC	21845	SDP1084MHG
5962-9864801HNA	21845	SDP1084NHD
5962-9864801HNC	21845	SDP1084NHG
5962-9864801HTA	21845	SDP1084THD
5962-9864801HTC	21845	SDP1084THG
5962-9864801HUA	21845	SDP1084UHD
5962-9864801HUC	21845	SDP1084UHG
5962-9864801HYA	21845	SDP1084YHD
5962-9864801HYC	21845	SDP1084YHG
5962-9864801HZA	21845	SDP1084ZHD
5962-9864801HZC	21845	SDP1084ZHG

- 1/ The lead finish shown for each PIN representing a hermetic package is the most readily available from the manufacturer listed for that part. If the desired lead finish is not listed contact the Vendor to determine its availability.
- 2/ The SMD device types listed above are similar to the device types listed on SMD 5962-89521.
- 3/ <u>Caution</u>. Do not use this number for item acquisition. Items acquired to this number may not satisfy the performance requirements of this drawing.

Vendor CAGEVendor namenumberand address

21845 Solitron Devices, Incorporated 3301 Electronics Way

West Palm Beach, FL 33407-4697

The information contained herein is disseminated for convenience only and the Government assumes no liability whatsoever for any inaccuracies in the information bulletin.